

Notice of References Cited

Application/Control No.

09/196,136

Applicant(s)/Patent Under

Reexamination

OHBAYASHI, SHIGEKI

Examiner

Guy J. Lamarre, P.E.

Art Unit

2133

Page 1 of 2

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,703,510	12-1997	Iketani et al.	327/143
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Ruparel et al. (A vertically integrated test methodology based on JTAG IEEE 1149.1 Standard Interface; IEEE, 27 Sept. 1991)
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

FORM PTO-892		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		SERIAL NO. 09/196,136	GROUP ART UNIT 2133	ATTACHMENT TO PAPER NO.	2
NOTICE OF REFERENCES CITED				APPLICANT(S) OHBAYASHI			
U.S. PATENT DOCUMENTS							
*		DOCUMENT NO.	DATE	NAME	CLASS	SUB- CLASS	FILING DATE
	A						
	B						
	C						
	D						
	E						
	F						
	G						
	H						
	I						
	J						
	K						
FOREIGN PATENT DOCUMENTS							
*		DOCUMENT NO.	DATE	COUNTRY	NAME	CLASS	SUB- CLASS
	L						
	M						
	N						
	O						
	P						
	Q						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)							
	R	Gallup et al (Testability features of the 68040; IEEE, 14 Sept. 1990)					
	S						
	T						
	U						
EXAMINER			DATE				
Guy J. Lamarre, P.E.			January 16, 2001		Form892ccs2106b		
* A copy of this reference is not being furnished with this office action. (See Manual of Patent Examining Procedure, section 707.05(a).)							